



MULTIPULS-1003-C1

Mobile dual circuit direct current pulse testing unit for surface crack detection and demagnetization of ferritic steel components

MULTIPULS-1003-C1

Magnetization

Fast, reliable Magnetization using direct current pulses

Simultaneous detection of all cracks

Dual electric circuit – alternating magnetization of the parts in 2 directions

High current magnetization

Magnetization with direct current pulses, applied crosswise to the part

Non-Contact MT-Testing

Non-contact magnetization of the part over a dual coil configuration

Demagnetization

Demagnetization using direct current pulses of declining intensity

Twin casing

Separate enclosures for power supply and testing unit – suitable for testing in narrow locations

Combined MT-testing

Magnetization with high current and coil

Integrated UV-Lamp with superimposed flood light

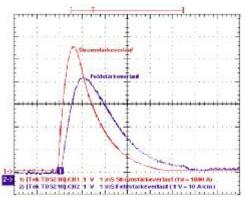
Uniform UV-lighting for clear crack indication. Superimposed flood light to sort out false crack indications





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Direct current pulse magnetization

Hirsch Multipuls 1003-C1 Technical Specifications	
Power supply:	230 VAC, 50/60 Hz
Power consumption:	1250 VA
Duty cycle:	50%
Test current:	500 A - 8,000 A
Field strength:	10 A/cm – 80 A/cm
Pulse frequency:	0.5 – 1 Hz
Number of pulses for Remagnetization:	1 – 99
Demagnetization time:	20 – 120 sec
Test cable length:	9.8' (16.4' on request) ((3.0 m (5 m on request))
UV-LED test lamp:	With white light, shock- protected
Coil cable:	Available on request
Dimensions W x H x L:	10.2" x 12.6" x 14.2" (260 x 320 x 360 mm)
Weight:	37.5lbs / 48.5 lbs (17 kg/ 22 kg)

- Pin sharp crack indication because of direct current pulse magnetization
- Clear crack indication already after 3 pulses = 3 sec
- High performance
- Compact design
- Low weight
- One-hand operation via remote control or UV-lamp
- Superimposed flood light for determination of wrong crack indications
- Interface for integration into a MT-testing machine
- Long service life
- · Long service intervals
- Low energy consumption
- · Low consumption of test fluid

